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(FILE 'USPAT' ENTERED AT 15:46:00 ON 07 AUG 96)

L1 10060 S DIFFEREN?(3A) PHASES
L2 19251 S PHASE(3A) (COMPUT? OR DETERMIN? OR CALCULAT?)
L3 9183 S AMPLITUDE(3A) (COMPUT? OR DETERMIN? OR CALCULAT?)
L4 1599 S L2 AND L3
L5 134 S L1 AND L4
L6 4 S L5 AND (356*374,375,376,369,365,355,354,356,357)/CCLS
L7 2460 S MOIRE
L8 15167 S GRATING
L9 0 S L5 AND L7
L10 7 S L5 AND L8
L11 8 S L4 AND L7
L12 56 S L4 AND L8
L13 49 S L12 NOT L10
L14 5 S L13 AND (356*374,375,376,369,364,354,355,356,357)/CCLS
=> d 16 1-4

1. 5,235,406, Aug. 10, 1993, Object displacement detection; Satoshi Ishii, et al., **356/356**, 358 [IMAGE AVAILABLE]

2. 4,850,711, Jul. 25, 1989, Film thickness-measuring apparatus using linearly polarized light; Kazuo Sano, et al., 356/382, **369** [IMAGE AVAILABLE]

3. 4,792,231, Dec. 20, 1988, Laser speckle imaging; David L. Fried, **356/354**; 364/525; 382/260, 280, 312 [IMAGE AVAILABLE]

4. 4,516,855, May 14, 1985, Method and apparatus for determining the polarization state of a light wave field; Hans E. Korth, 356/367; 348/32; **356/369** [IMAGE AVAILABLE]
=> d 110 1-7

1. 5,534,970, Jul. 9, 1996, Scanning exposure apparatus; Toshiharu Nakashima, et al., 355/53; 353/122; 355/67, 71; 359/589, 622 [IMAGE AVAILABLE]

2. 5,384,573, Jan. 24, 1995, Image synthesis using time sequential holography; Terry M. Turpin, 342/179; 128/653.1; 359/32; 364/413.19, 822; 378/87 [IMAGE AVAILABLE]

3. 5,235,406, Aug. 10, 1993, Object displacement detection; Satoshi Ishii, et al., 356/356, 358 [IMAGE AVAILABLE]

4. 4,792,231, Dec. 20, 1988, Laser speckle imaging; David L. Fried, 356/354; 364/525; 382/260, 280, 312 [IMAGE AVAILABLE]

5. 4,665,366, May 12, 1987, NMR imaging system using phase-shifted signals; Albert Macovski, 324/309, 307 [IMAGE AVAILABLE]

6. 4,087,842, May 2, 1978, Recording track eccentricity compensation method and means; William A. Manly, 360/77.06, 77.02, 109 [IMAGE AVAILABLE]

7. 4,030,118, Jun. 14, 1977, Color encoding camera utilizing comb filtering for color signal separation; Robert Adams Dischert, 358/331; 348/291, 292; 358/329 [IMAGE AVAILABLE]
=> d 114 1-5

1. 5,442,172, Aug. 15, 1995, Wavefront reconstruction optics for use in a disk drive position measurement system; Wen-Wei Chiang, et al., 250/237G; **356/354**; 360/75, 77.03 [IMAGE AVAILABLE]

2. 5,432,607, Jul. 11, 1995, Method and apparatus for inspecting patterned thin films using diffracted beam ellipsometry; Marc A. Taubenblatt, **356/364**; 250/206.1, 206.2; 356/237, 401 [IMAGE AVAILABLE]

3. 4,705,400, Nov. 10, 1987, Shearing phase difference sensor; Brent L. Ellerbroek, et al., 356/353, **354** [IMAGE AVAILABLE]

4. 4,672,196, Jun. 9, 1987, Method and apparatus for measuring properties of thin materials using polarized light; Lawrence S. Canino, 250/225, 559.09, 559.28; **356/369** [IMAGE AVAILABLE]

5. 4,212,073, Jul. 8, 1980, Method and system for surface contouring; N. Balasubramanian, 364/562; **356/375**, **376**; 364/525 [IMAGE AVAILABLE]
=> d 111 1-8

1. 5,432,349, Jul. 11, 1995, Fourier transform microscope for x-ray and/or gamma-ray imaging; Kent S. Wood, et al., 250/336.1; 378/43, 149 [IMAGE AVAILABLE]

2. 5,117,698, Jun. 2, 1992, Pulse train detection in transit time flowmeter; Joseph Baumoel, 73/861.28 [IMAGE AVAILABLE]

3. 4,626,907, Dec. 2, 1986, Method and apparatus for mutually aligning objects; Franz Schedewie, 348/95; 356/401 [IMAGE AVAILABLE]

4. 4,519,001, May 21, 1985, Apparatus for providing dropout compensation and error concealment in a PAL format video information signal; Eric F. Morrison, 358/310, 314, 328; 371/31, 65 [IMAGE AVAILABLE]

5. 4,212,073, Jul. 8, 1980, Method and system for surface contouring; N.

Balasubramanian, 364/562; 356/375, 376; 364/525 [IMAGE AVAILABLE]

6. 4,130,348, Dec. 19, 1978, Optical system for a coherent light illuminating source; Masana Minami, 359/563, 28 [IMAGE AVAILABLE]

7. 3,919,881, Nov. 18, 1975, Temporal reference wavefront reconstruction process and system; Alexander F. Metherell, 73/604, 656; 359/9, 10, 901; 367/10 [IMAGE AVAILABLE]

8. 3,890,035, Jun. 17, 1975, COMPLEX LIGHT SPATIAL MODULATOR; Yasutsugu Takeda, 359/250, 21, 303 [IMAGE AVAILABLE]

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E BIEMAN, L/IN
L15 1 S E4
=> d

1. 4,647,208, Mar. 3, 1987, Method for spatial measurement of holes;
Leonard H. Bieman, 356/375; 348/94; 356/237, 394 [IMAGE AVAILABLE]
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